

## Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FQD3N50C	FQD3N50CTM	D-PAK	380mm	16mm	2500
FQD3N50C	FQD3N50CTF	D-PAK	380mm	16mm	2500
FQU3N50C	FQU3N50CTU	I-PAK	-	-	70

## Electrical Characteristics T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit	
Off Characteristics							
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA	500	--	--	V	
ΔBV <sub>DSS</sub> /ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced to 25°C	--	0.7	--	V/°C	
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 500 V, V <sub>GS</sub> = 0 V	--	--	1	μA	
		V <sub>DS</sub> = 400 V, T <sub>C</sub> = 125°C	--	--	10	μA	
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 30 V, V <sub>DS</sub> = 0 V	--	--	100	nA	
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = -30 V, V <sub>DS</sub> = 0 V	--	--	-100	nA	
On Characteristics							
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250 μA	2.0	--	4.0	V	
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 1.25 A	--	2.1	2.5	Ω	
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 40 V, I <sub>D</sub> = 1.25 A (Note 4)	--	1.5	--	S	
Dynamic Characteristics							
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V, f = 1.0 MHz	--	280	365	pF	
C <sub>oss</sub>	Output Capacitance		--	50	65	pF	
C <sub>rss</sub>	Reverse Transfer Capacitance		--	8.5	11	pF	
Switching Characteristics							
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = 250 V, I <sub>D</sub> = 2.5A, R <sub>G</sub> = 25 Ω	--	10	30	ns	
t <sub>r</sub>	Turn-On Rise Time		--	25	60	ns	
t <sub>d(off)</sub>	Turn-Off Delay Time		(Note 4, 5)	--	35	80	ns
t <sub>f</sub>	Turn-Off Fall Time			--	25	60	ns
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> = 400 V, I <sub>D</sub> = 2.5A, V <sub>GS</sub> = 10 V	--	10	13	nC	
Q <sub>gs</sub>	Gate-Source Charge		--	1.5	--	nC	
Q <sub>gd</sub>	Gate-Drain Charge	(Note 4, 5)	--	5.5	--	nC	
Drain-Source Diode Characteristics and Maximum Ratings							
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current		--	--	2.5	A	
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current		--	--	10	A	
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 2.5 A	--	--	1.4	V	
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 3 A, dI <sub>F</sub> / dt = 100 A/μs	--	170	--	ns	
Q <sub>rr</sub>	Reverse Recovery Charge	(Note 4)	--	0.7	--	μC	

### NOTES:

1. Repetitive Rating : Pulse width limited by maximum junction temperature
2. L = 58mH, I<sub>AS</sub> = 2.5A, V<sub>DD</sub> = 50V, R<sub>G</sub> = 25 Ω, Starting T<sub>J</sub> = 25°C
3. I<sub>SD</sub> ≤ 2.5A, di/dt ≤ 200A/μs, V<sub>DD</sub> ≤ BV<sub>DSS</sub>, Starting T<sub>J</sub> = 25°C
4. Pulse Test : Pulse width ≤ 300μs, Duty cycle ≤ 2%
5. Essentially independent of operating temperature

## Typical Performance Characteristics

Figure 1. On-Region Characteristics

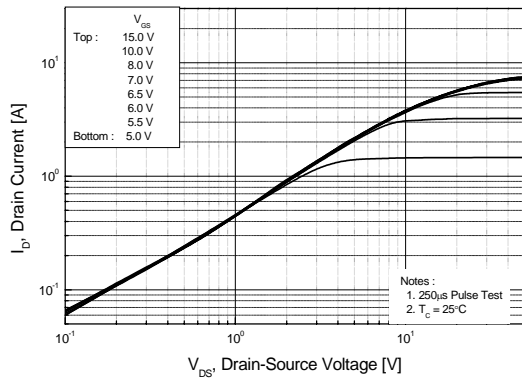


Figure 2. Transfer Characteristics

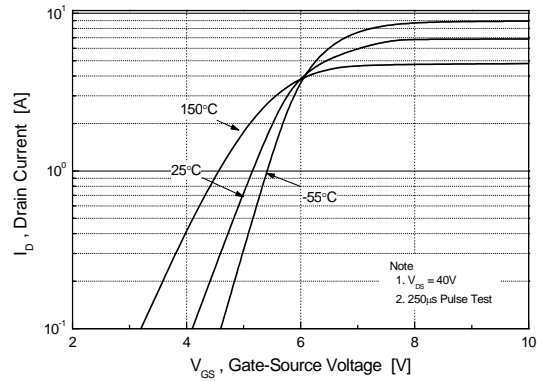


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

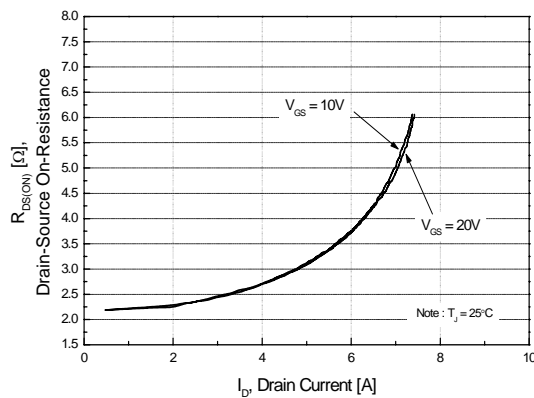


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

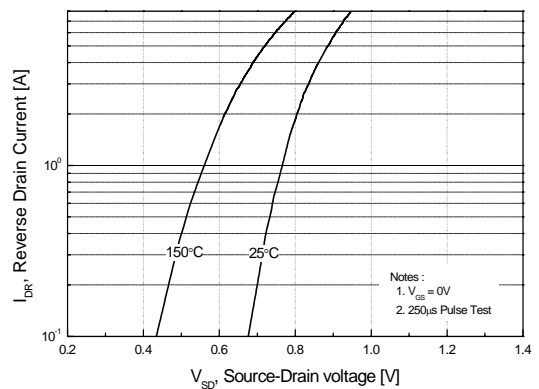


Figure 5. Capacitance Characteristics

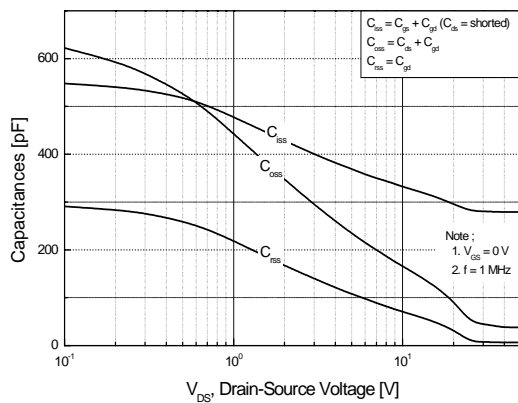
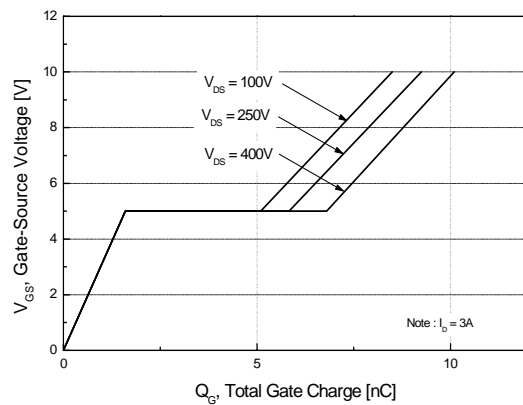
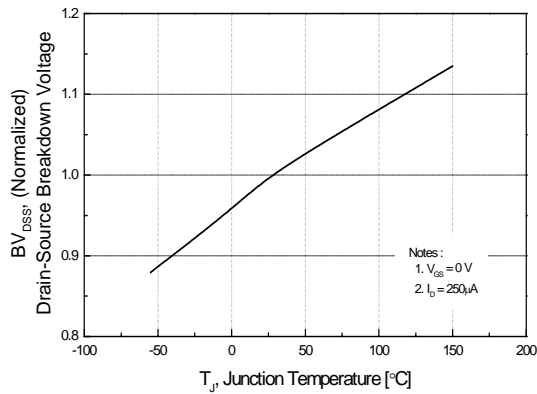


Figure 6. Gate Charge Characteristics

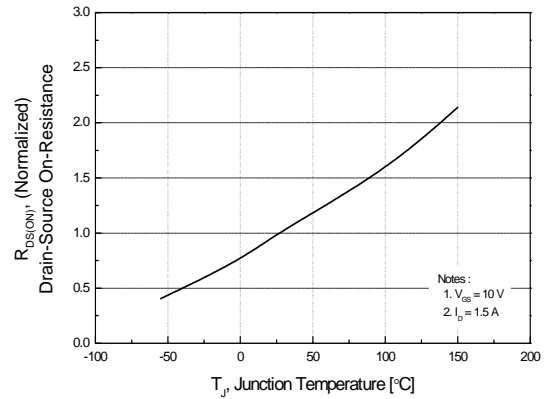


## Typical Performance Characteristics (Continued)

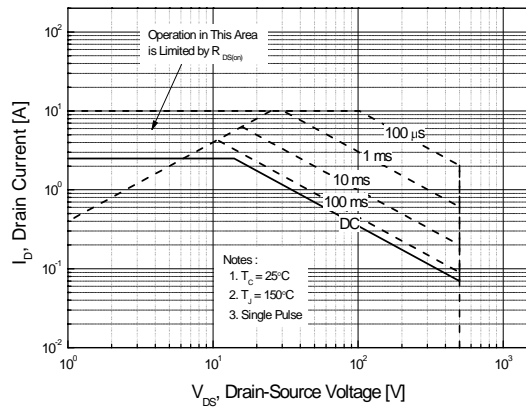
**Figure 7. Breakdown Voltage Variation vs. Temperature**



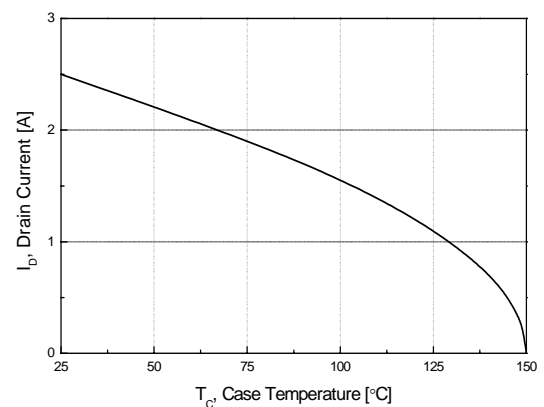
**Figure 8. On-Resistance Variation vs. Temperature**



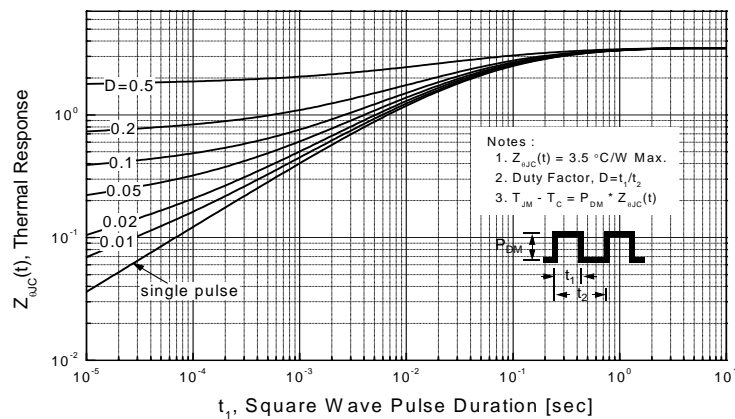
**Figure 9. Maximum Safe Operating Area**



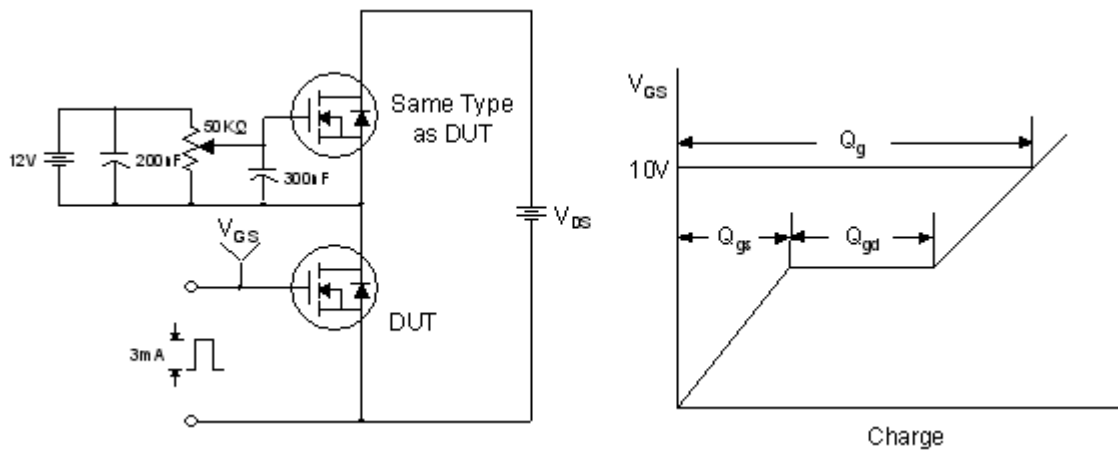
**Figure 10. Maximum Drain Current vs. Case Temperature**



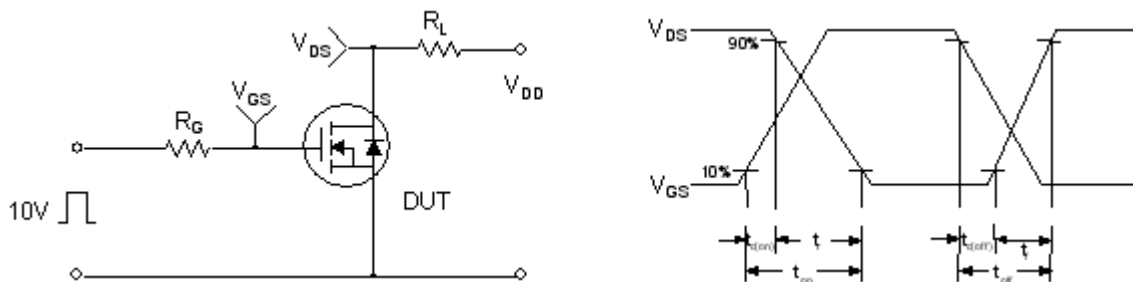
**Figure 11. Transient Thermal Response Curve**



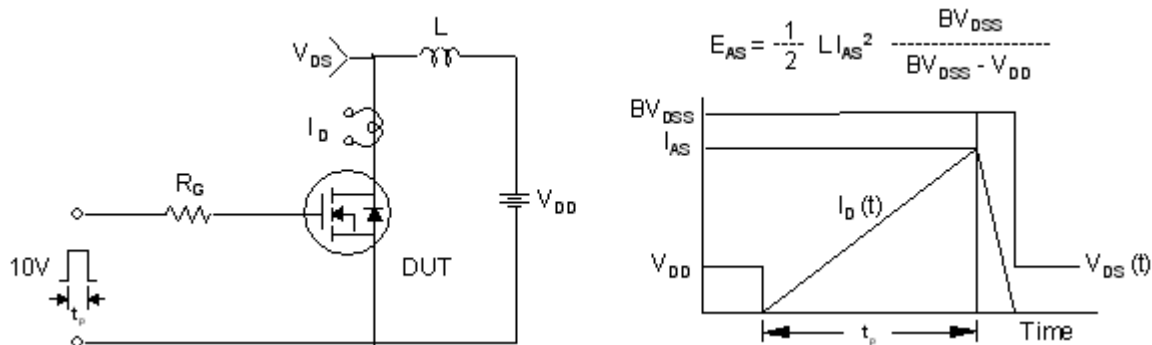
### Gate Charge Test Circuit & Waveform



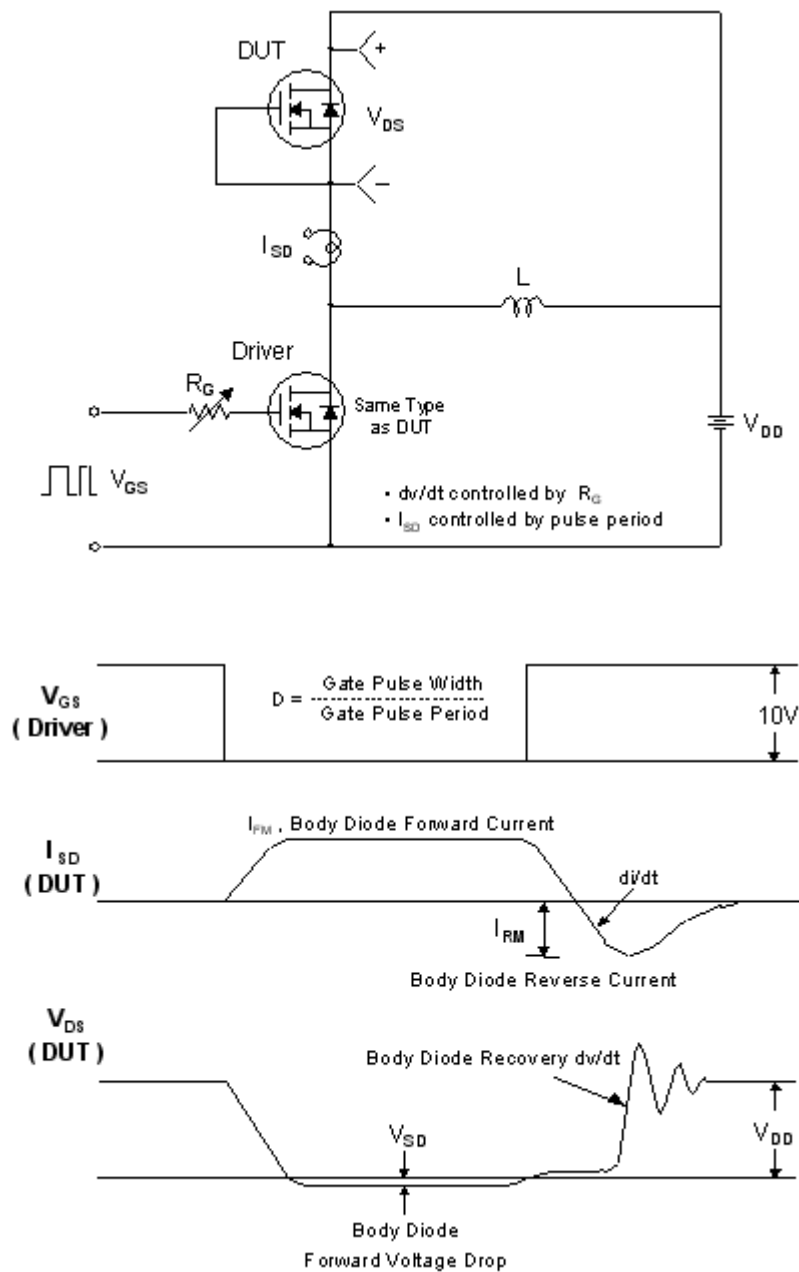
### Resistive Switching Test Circuit & Waveforms



### Unclamped Inductive Switching Test Circuit & Waveforms

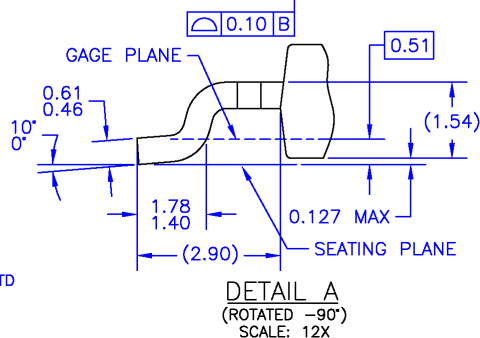
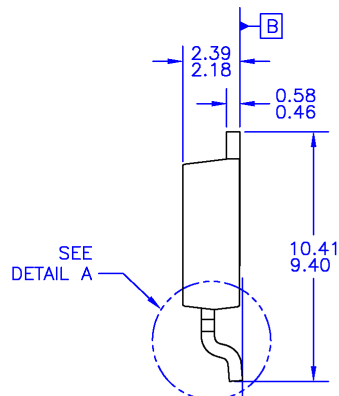
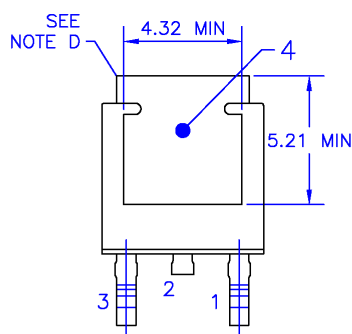
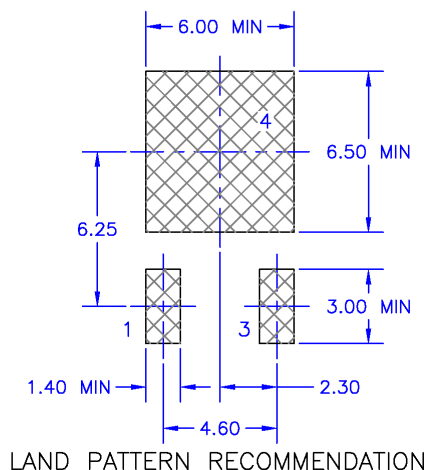
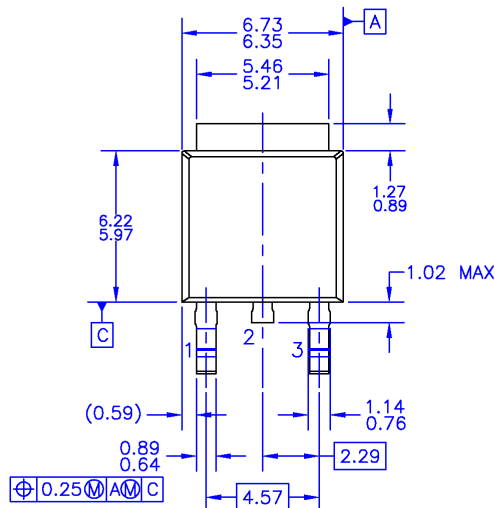


# Peak Diode Recovery dv/dt Test Circuit & Waveforms



# Mechanical Dimensions

## D-PAK

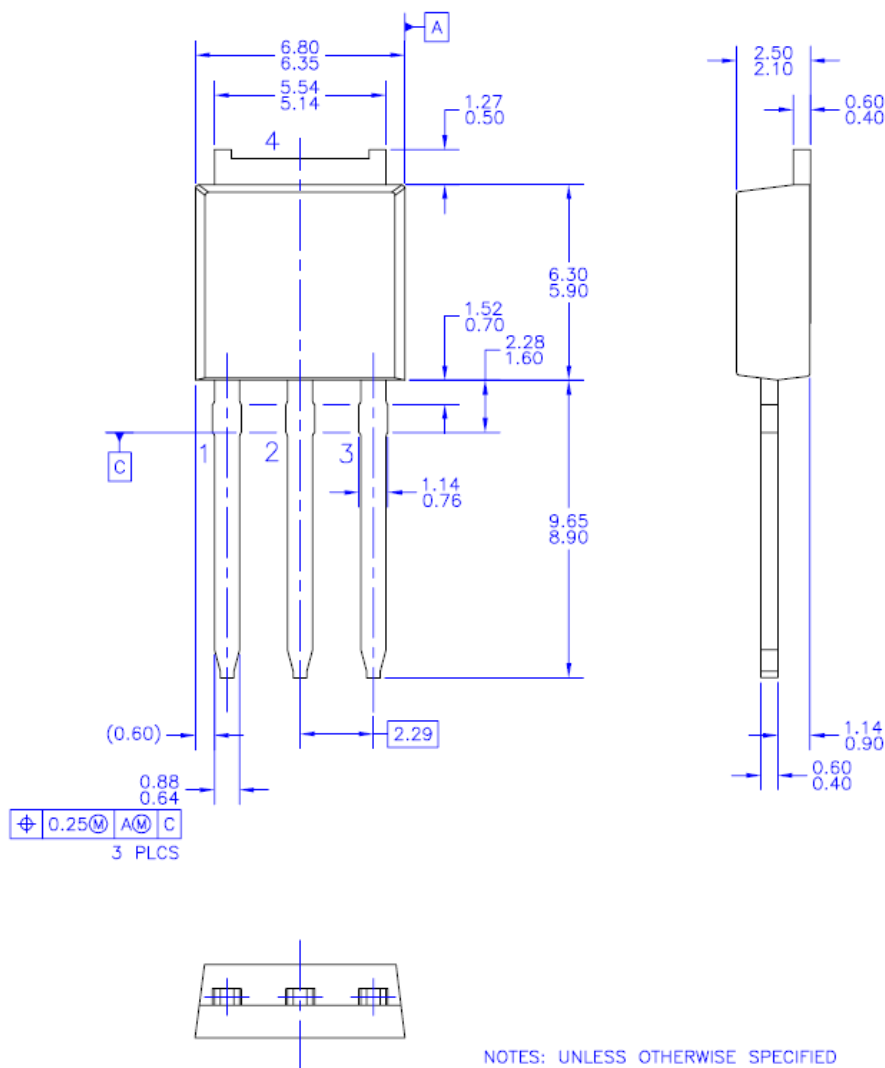


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  - B) ALL DIMENSIONS ARE IN MILLIMETERS.
  - C) DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.
  - D) HEAT SINK TOP EDGE COULD BE IN CHAMFERED CORNERS OR EDGE PROTRUSION.
  - E) PRESENCE OF TRIMMED CENTER LEAD IS OPTIONAL.
  - F) DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH AND TIE BAR EXTRUSIONS.
  - G) LAND PATTERN RECOMMENDATION IS BASED ON IPC7351A STD TO220P1003X238-3N.
  - H) DRAWING NUMBER AND REVISION: MKT-TO252A03REV8

Dimensions in Millimeters

# Mechanical Dimensions

## I-PAK



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